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IEEE Electron Device Letters , Volume: 21 Issue: 12 , Dec. 2000

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[\[Abstract\]](#) [\[PDF Full-Text \(64 KB\)\]](#) **JNL****2 Anodization for forming thin film embedded capacitors in MCM-D and MCM substrates***Nelms, D.; Ulrich, R.; Schaper, L.; Reeder, S.*

Electronic Components &amp; Technology Conference, 1998. 48th IEEE , 1998

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[\[Abstract\]](#) [\[PDF Full-Text \(476 KB\)\]](#) **CNF****3 Formation and magneto-structural properties of the new Nd/<sub>3</sub>/Fe/<sub>29-x</sub>/W/<sub>x</sub> intermetallic phase***Sanchez, J.L.; Neiva, A.C.; Marques, J.M.; Missell, F.P.; de Amorin, H.S.; Domingues P.H.; Amaral, M.R., Jr.*

Magnetics, IEEE Transactions on , Volume: 33 Issue: 5 Part: 2 , Sept. 1997

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